

**MOTOROLA**

## Phase-Frequency Detector

**ELECTRICALLY TESTED PER:  
5962-8775201**

The 12540 is a phase-frequency detector intended for use in systems requiring zero phase and frequency difference at lock. In combination with a voltage controlled oscillator (such as the 1648), it is useful in a broad range of phase-locked loop applications. Operation of this device is identical to that of the Phase Detector #1 of the 4044.

- Operating Frequency = 80 MHz typical

ABSOLUTE MAXIMUM RATINGS	Symbol	Min.	Max.	Units
Supply Voltage	$V_{CC}$		+7.0	$V_{dc}$
Output Voltage	$V_{OUT}$		+5.5	$V_{dc}$
Input Voltage	$V_{IN}$		+5.5	$V_{dc}$
Operating Temperature Range	$T_A$	-55	+125	$^{\circ}C$
Storage Temperature Range	$T_{stg}$	-65	+175	$^{\circ}C$

### PIN ASSIGNMENTS

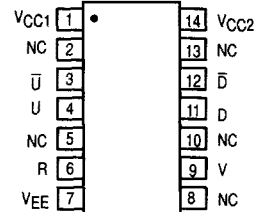
FUNCTION	DIL	BURN-IN (CONDITION C)
$V_{CC1}$	1	GND
NC	2	OPEN
$\bar{U}$	3	51 $\Omega$ to $V_{TT}$
U	4	51 $\Omega$ to $V_{TT}$
NC	5	OPEN
R	6	2 k $\Omega$ to $V_{TT}$
VEE	7	$V_{CC}$
NC	8	OPEN
V	9	2 k $\Omega$ to $V_{TT}$
NC	10	OPEN
D	11	51 $\Omega$ to $V_{TT}$
$\bar{D}$	12	51 $\Omega$ to $V_{TT}$
NC	13	OPEN
$V_{CC2}$	14	GND

**BURN - IN CONDITIONS:**  
 **$V_{CC} = 6.0 V \text{ MAX/ } 5.0 V \text{ MIN}$**

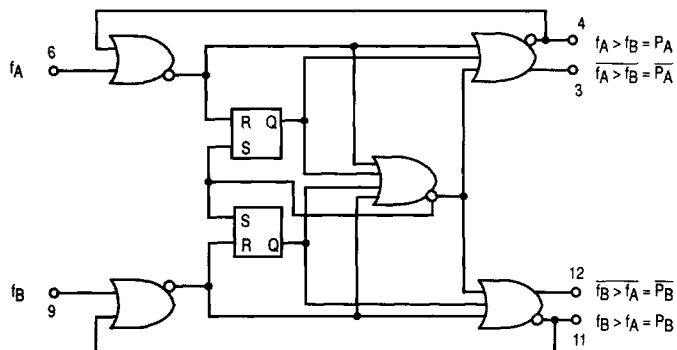
**Military 12540**

### AVAILABLE AS

- 1) JAN: N/A
- 2) SMD: 5962-8775207
- 3) 883: 12540/BXAJC

**X = CASE OUTLINE AS FOLLOWS:****PACKAGE: CERPDP: C**

### LOGIC DIAGRAM



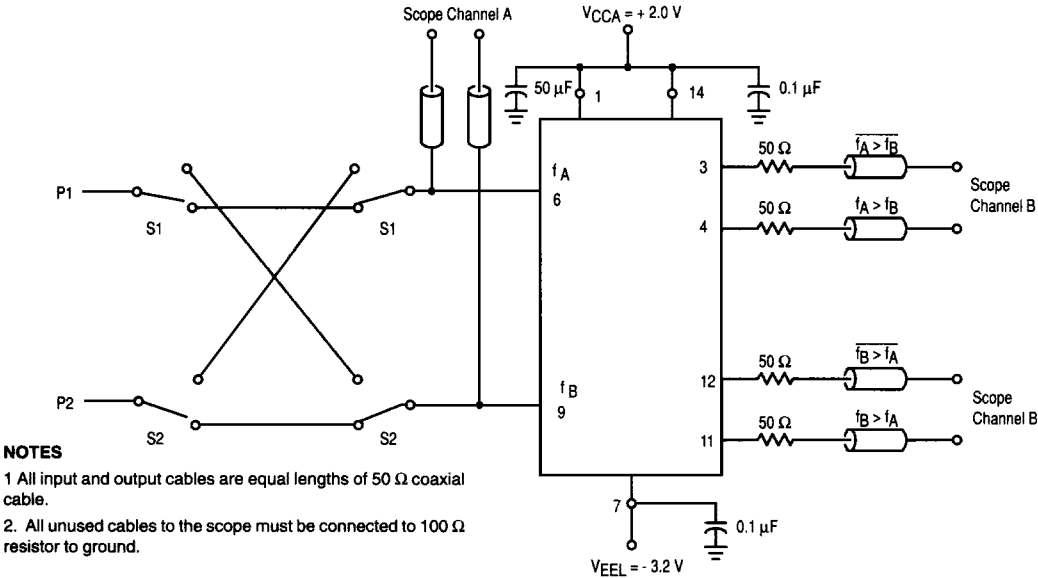
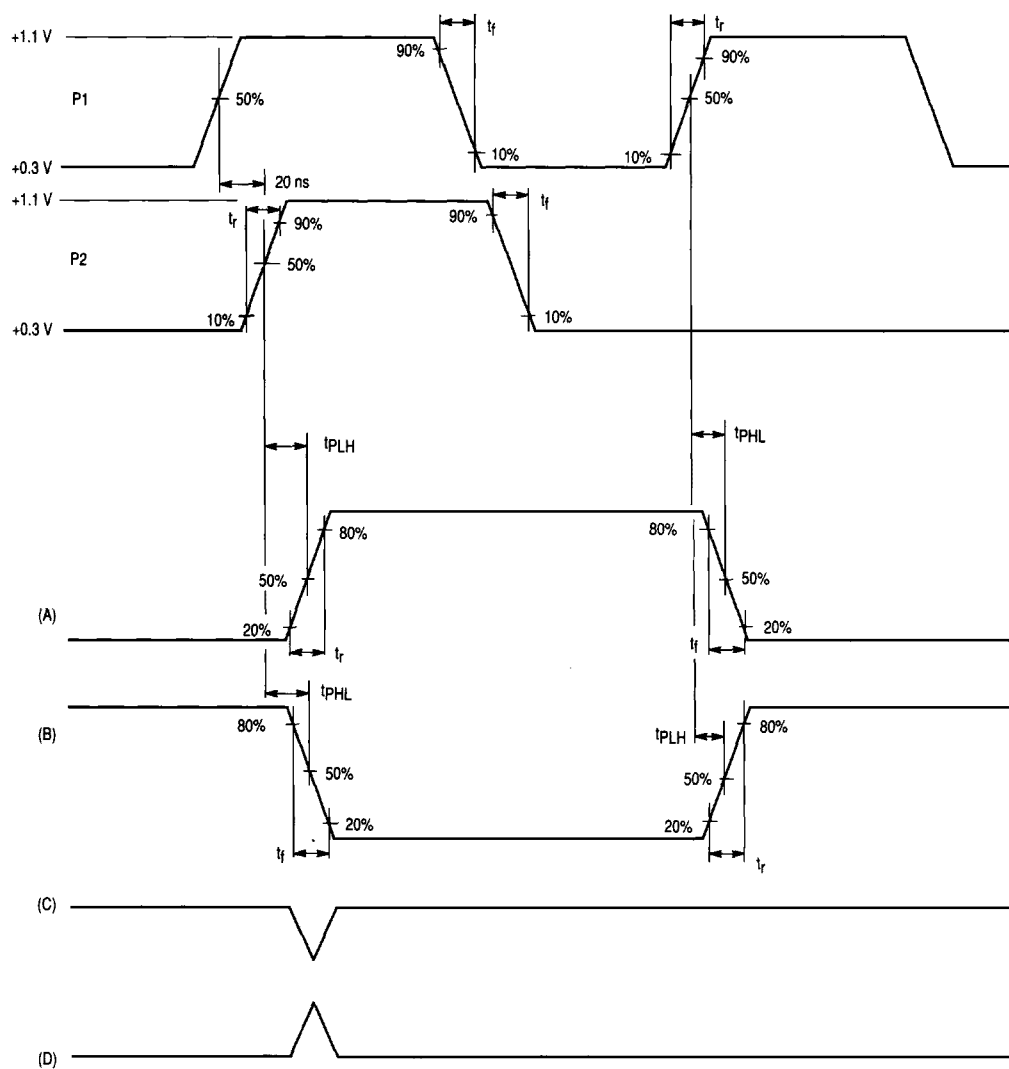


Figure 1. Switching Test Circuit

Functional Truth Table

INPUT		OUTPUT			
f <sub>A</sub>	f <sub>B</sub>	f <sub>A</sub> > f <sub>B</sub>	f <sub>B</sub> > f <sub>A</sub>	f <sub>A</sub> > f <sub>B</sub>	f <sub>B</sub> > f <sub>A</sub>
0	0	X	X	X	X
0	1	X	X	X	X
1	1	X	X	X	X
0	1	X	X	X	X
1	1	1	0	0	1
0	1	1	0	0	1
1	1	1	0	0	1
1	0	1	0	0	1
1	1	0	0	1	1
1	0	0	0	1	1
1	1	0	1	1	0
1	0	0	1	1	0
1	1	0	1	1	0
0	1	0	1	1	0
1	1	0	0	1	1

X = DON'T CARE

**NOTES**

1. P1, P2:

- a) PRF = 5.0 MHz.
- b) Duty Cycle 50%.
- c)  $t_r = t_f = 1.5 \text{ ns} \pm 0.2 \text{ ns}$  (10% to 90%)

**Figure 2. Test Circuit Waveforms**

12540

Test Temperature	Test Voltage Values (Volts)					
	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IHA</sub>	V <sub>ILA</sub>	V <sub>CC</sub>	V <sub>EE</sub>
T <sub>A</sub> = 25 °C	+ 4.22	+3.21	+3.895	+3.525	+5.0	0
T <sub>A</sub> = 125 °C	+ 4.37	+3.24	+4.000	+3.600	+5.0	0
T <sub>A</sub> = -55 °C	+4.12	+3.14	+3.745	+3.490	+5.0	0

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW					
	Functional Parameters:	+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments Output Load = 100 kΩ to + 3.0 V					
		Subgroup 1		Subgroup 2		Subgroup 3			V <sub>IH</sub>	R - 1	V <sub>EE</sub>	*	V <sub>CC</sub>	P.U.T.
		Min	Max	Min	Max	Min	Max							
V <sub>OH</sub>	High Voltage Output	4.07	4.22	4.175	4.37	3.92	4.12	V		3, 4, 11, 12	7	6, 9	1, 14	3, 4, 11, 12
V <sub>OL</sub>	Low Voltage Output	3.21	3.44	3.24	3.515	3.14	3.405	V		3, 4, 11, 12	7	7, 9	1, 14	3, 4, 11, 12
V <sub>OHA</sub>	Threshold Voltage High	4.05	4.22	4.155	4.37	3.90	4.12	V		3, 4, 11, 12	7	7, 9	1, 14	3, 4, 11, 12
V <sub>OLA</sub>	Threshold Voltage Low	3.21	3.46	3.24	3.535	3.14	3.425	V		3, 4, 11, 12	7	7, 9	1, 14	3, 4, 11, 12
I <sub>INH</sub>	Input Current High		350					μA	6, 9		7		1, 14	6, 9
I <sub>E</sub>	Total Power Supply Current	-115	-80					μA			7		1, 14	7

**NOTE:** (This device will meet standard MECL logic levels using  $V_{EE} = -5.2$  Vdc and  $V_{CC} = 0$ V).

1. The outputs of the device must be tested by sequencing through the truth table for  $V_{OH}$ . VOL tests.
2. The outputs of the device must be tested by sequencing through the truth table for  $V_{OHA}$ . VOLA tests.

All input, power supply, and ground voltages must be maintained between tests.

3. Preconditioning for AC tests is accomplished by applying P1 for a minimum of two pulses prior to P2.

\* = Per truth table.

# 12540 QUIESCENT LIMIT TABLE

Test Temperature	Test Voltage Values (Volts)					
	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IHA</sub>	V <sub>ILA</sub>	V <sub>CC</sub>	V <sub>EEL</sub>
T <sub>A</sub> = 25 °C	+ 4.22	+ 3.21	+ 3.895	+ 3.525	+ 2.0	-3.0 or -3.2
T <sub>A</sub> = 125 °C	+ 4.37	+ 3.24	+ 4.000	+ 3.600	+ 2.0	-3.0 or -3.2
T <sub>A</sub> = -55 °C	+ 4.12	+ 3.14	+ 3.745	+ 3.490	+ 2.0	-3.0 or -3.2

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW							
	Functional Parameters:	+ 25 °C		+ 125 °C				- 55 °C		Pinouts referenced are for DIL package, check Pin Assignments Output Load = 100 kΩ to 0.0 V						
		Subgroup 9		Subgroup 10		Subgroup 11										
		Min	Max	Min	Max	Min	Max									
t <sub>r</sub>	Rise Time		3.4		3.8		3.4	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>f</sub>	Fall Time		3.4		3.8		3.4	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>6+4+</sub> )	0	4.6	0	5.0	0	4.6	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>6+12+</sub> )	0	6.0	0	6.6	0	6.0	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>6+3+</sub> )	0	4.5	0	4.9	0	4.5	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>6+11+</sub> )	0	6.4	0	7.0	0	6.4	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>9+11+</sub> )	0	4.6	0	5.0	0	4.6	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>9+3+</sub> )	0	6.0	0	6.6	0	6.0	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>9+12+</sub> )	0	4.5	0	4.9	0	4.5	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		
t <sub>pd</sub>	Propagation Delay (t <sub>9+4+</sub> )	0	6.4	0	7.0	0	6.4	ns	3, 4, 11, 12	1, 14	8, 9	8, 9	7	3, 4, 11, 12		